

<p align="center">FIRST INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(use as many sheets as necessary)</small></p>		Complete if Known	
		Application Number	10/721,232
		Filing Date	November 26, 2003
		First Named Inventor	Rolf FREIMANN, et al.
		Examiner Name	Unassigned
Attorney Docket Number	007413-068		

U.S. PATENT DOCUMENTS				
Examiner TRADEMARK OFFICE	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)
SAT	4,732,483		Biegen	03-22-1988
↑	4,340,306		Balasubramanian	07-20-1982
	5,473,434		de Groot	12-05-1995
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NON-PATENT LITERATURE DOCUMENTS	
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
SAT	Patrick P. Naulleau, et al., "Extreme-Ultraviolet Phase-Shifting Point-Diffraction Interferometer: A Wave-Front Metrology Tool with Subangstrom Reference-Wave Accuracy," Applied Optics, Vol. 38, No. 35, December 10, 1999, pages 7252-7263, Optical Society of America
	Daniel Malacara, Ed., "Optical Shop Testing," Second Edition, 1992, Chapter 1.2, pages 18-49, John Wiley & Sons, Inc., New York
	Daniel Malacara, Ed., "Optical Shop Testing," Second Edition, 1992, Chapter 2.1, pages 51-53, John Wiley & Sons, Inc., New York
SAT	Daniel Malacara, Ed., "Optical Shop Testing," Second Edition, 1992, Chapter 2.6, pages 73-77, John Wiley & Sons, Inc., New York

Examiner Signature	S.A. Turner	Date Considered	1-10-06
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***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.